

#### Electromagnetic interactions and transport of charged particles (e<sup>-</sup>, e<sup>+</sup>, muons, charged hadrons, ions)

Overview of lepton and photon interactions

Transport of charged particles

Particle transport and delta-ray-production thresholds (exercise!)

#### Beginner course - ULB, May 2022

#### Outline

#### Coulomb scattering

Elastic scattering of charged particles on screened electrostatic potential of target atoms

- Condensed multiple Coulomb scattering
- Single scattering

#### Stopping power for ionizing particles

- Continuous energy loss along a particle step: stopping power (dE/dx) description + fluctuations
- Discrete energy losses (delta ray production)

#### Photon and electron interactions in matter

- Radiation length
- e<sup>±</sup> : Radiative losses (Bremsstrahlung)
- γ : photo-electric, Compton, pair production
- $\gamma$ : a note on photonuclear

#### lons

- Corrections in the stopping power: effective charge, Mott correction, etc.
- Additional EM processes: direct e-/e+ pair production, electromagnetic dissociation



#### **Coulomb scattering**



### The problem

- Charged particles are elastically scattered from (screened) electrostatic potential of atoms
- Elastic collisions are very frequent





# How frequent ??

- **EMFP**: mean free path between consecutive Coulomb scattering
- **IMFP**: mean free path between consecutive ionization losses
- RANGE: estimated distance traveled to rest
- Estimate number of ionization losses:
  - N=RANGE/IMFP
  - e.g. for a 1-MeV electron, N~10<sup>4</sup>
- Estimate number of Coulomb losses:
  - N=RANGE/EMFP
  - e.g. for a 1-MeV electron, N~10<sup>4</sup>
- Too many to simulate explicitly!



• A more practical approach is necessary to keep CPU time within acceptable bounds.



### The problem

- Charged particles are elastically scattered from (screened) electrostatic potential of atoms
- Elastic collisions are very frequent
  - $\rightarrow$  Impractical to sample individually
- **Multiple** scattering theory: effective scheme to describe effect of many deflections along a particle step

After a given step length, what does the angular distribution look like?





### **The Moliere distribution**

- In FLUKA we use an algorithm based on the Moliere multiple-scattering theory
- Basic assumptions:
  - Differential cross section in an individual collision: screened Rutherford

$$\frac{\mathrm{d}\sigma_{\mathrm{mol}}}{\mathrm{d}\Omega} = \left[\frac{z^2 Z^2 e^4}{4c^4 \beta^2 E^2 \sin^4 \frac{1}{2}\theta}\right] \left[\frac{\left(1-\cos\theta\right)^2}{\left(1-\cos\theta+\frac{1}{2}\chi_{\mathrm{a}}^2\right)^2}\right]$$

- Solve the transport equation within the small-angle approximation.
- Analytical manipulations -> minimum applicable step length (energy-dependent)

• Distribution of angles after step t:  

$$F_{Mol}(\theta,t)d\Omega = 2\pi\chi d\chi \left[ 2e^{-\chi^2} + \frac{1}{B}f_1(\chi) + \frac{1}{B^2}f_2(\chi) + \dots \right] \left[ \frac{\sin\theta}{\theta} \right]^{\frac{1}{2}}$$

$$f_n(\chi) = \frac{1}{n!} \int_0^\infty u \, du \, J_0(\chi u) e^{-u^2/4} \left( \frac{u^2}{4} \ln \frac{u^2}{4} \right)^n$$

- At every step t, we sample aggregate deflection from  $\mathsf{F}_{\mathsf{Mol}}$ 



#### User control of multiple-Coulomb-scattering algorithm

- There are situations where the Moliere theory is not applicable:
  - Transport in residual gas
  - Interactions in thin geometries like wires or slabs (few elastic collisions)
  - Electron spectroscopies at sub-10-keV energies
  - Micro-dosimetry
- One can request to switch single scattering on via the MULSOPT card
- The scope of this card is large. We focus on a few aspects only:

➢ MULSOPT Type: GLOBEMF ▼ Min step: Stretching: ▼
Optimal: Single scat: On ▼ E<Moliere: On ▼ # scatterings: 2</p>

- "Single scat": switch on single scattering at boundaries or for too short steps
- "E<Moliere": resort to single scattering for energies too low for Moliere theory to apply
- "# of scatterings": number of single scattering events approaching boundary
- Likewise for charged hadrons and muons, with SDUM=GLOBHAD



### Model performance in demanding circumstances

- As a result of the modelling effort, even demanding situations like electron backscattering can be modelled, in most cases without resorting to single scattering (not bad for an algorithm based on the Moliere theory!)
- E.g.: 1.75 MeV electrons on 0.364 g/cm<sup>2</sup> Cu foil
- Transmitted (forward scattered) and backscattered electron angular distributions.
- Dots: experimental data Curves: FLUKA





# Electronic energy loss of heavy charged particles



### The problem

- Fast charged particles interact with matter electrons, and lose part of their energy
  - Ionization

Excitation

- of atoms along their passage
- In most cases, the energy transfer is small !
- Very large number of such interactions taking place
  - $\rightarrow$  Impractical to sample individually (again...)

(see slide 5)



After a given step length, what does the energy distribution look like?

...and what of the energy lost ?



# **Ionization energy losses**

#### Two different treatments: **small** vs **large** energy losses





### **Delta-ray production threshold**



- $T_{\delta}$  = delta-ray production threshold
- FLUKA sets default values, not necessarily appropriate for your problem!
- Cards to override (rule of thumb below):
  - Electrons and positrons: EMFCUT card with SDUM=PROD-CUT

★ EMFCUT Type: PROD-CUT ▼ e-e+ Threshold: Kinetic ▼ e-e+ Ekin: 1e-05 y 1e-6 Fudgem: 1e-5 Mat: ALUMINUM ▼ to Mat: ALUMINUM ▼ Step:

Charged hadrons, muons, and ions: **DELTARAY** card

DELTARAY E three: 1e-5 # Log dp/dx: Log width dp/dx: Print: NOPRINT Mat: ALUMINUM to Mat: ALUMINUM Step:



# **Energy loss distributions**

 Experimental (blue dots) vs simulated (red dots) energy loss distributions for 2 GeV/c positrons (left) and protons (right) traversing 100 um of Si.



- Skewed Landau-Vavilov distribution (+ corrections depending on projectile)
- J. Bak et al, NPB 288, 681 (1987)



# Printing the electronic stopping power

• Electrons and positrons: **EMFFIX** and SDUM=PRINT

EMFFIX Mat1: ALUMINUM 
Max Frac.1: Print: PRINT 
Mat2: 
Max Frac.2:
Mat3: 
Max Frac.3:

Charged particles: DELTARAY and SDUM=PRINT

DELTARAY E thres: 1e-5 # Log dp/dx: Log width dp/dx: Print: PRINT V Mat: ALUMINUM V to Mat: ALUMINUM V Step:

 If requested, the stopping power is printed in the .out file (requires minimal scripting to extract and plot)



### **Electronic energy loss overview**

Example of printing from FLUKA

Check easily that all energy loss curves are consistent with each other (dependence on Z)





## **Depth-dose distribution of <sup>238</sup>U in steel**

- All charged particles share the same approach.
- Heavy ions require the following refinements:

```
Effective charge (up-to-date parametrizations for Z>1)
```

Mott cross section

Nuclear form factor of projectile ion in delta-ray production

Direct e-/e+ production

Ref: U.I. Uggerhøj, <u>Mat. Fys. Medd. Dan. Vid. Selsk., vol. 52, 699-729 (2006)</u>





### Summary : electronic energy loss for heavy particles

#### 2 treatments for ionization energy losses in FLUKA

- large energy losses : δ ray emission (transported explicitly)
- small energy losses : aggregated and described along particle step
- Importance of the  $\delta$ -ray threshold !

#### • Reality (as always) more complex:

- Low energy : non-relativistic Ziegler, LSS,...
- High energy : radiative losses become predominant
- Dedicated effort for ions leads to good agreement with experiments



# **FLUKA card summary**

EMFCUT : set delta ray production threshold for electrons and positrons
EMFFIX : print stopping power for electrons and positrons
DELTARAY : set delta ray production threshold for muons and charged hadrons
+ print stopping power for charged hadrons and muons



#### Photon and e<sup>±</sup> interactions in matter



#### **Photon interactions**



(Figures kindly shared by the PENELOPE authors)



## **Photon interaction cross sections**

#### Low energy

- photoelectric effect  $\sigma \propto Z^5$
- atomic shell structure signature

#### Intermediate energy

Compton scattering

#### High energy

- At 1.022 MeV, e-/e+ pair production opens

   σ ∝ Z<sup>2</sup>
- Minor contribution from photonuclear





# **Electron/positron interactions**

#### **Below critical energy**

- Ionization (cf. before) with a twist, due to projectile and target symmetry
- **Møller** (e-) or **Bhabha** (e+) scattering ( $\rightarrow \delta$ -rays)

#### Above the critical energy

- Bremstrahlung (radiative losses)
  - Differential cross sections from the Berger and Seltzer (NIST) database
  - Consideration of Landau-Pomeranchuk-Migdal effect

#### Positron annihilation

- Both at rest and in flight
- For annihilation at rest, account for mutual polarization of the two emitted photons
- + electro-nuclear... (see hadronic physics)





# Photon and e<sup>±</sup> physics package in FLUKA

 FLUKA's e<sup>±</sup> and γ physics package (EMF) is already enabled with most DEFAULTS, except: EET-TRAN, NEUTRONS, SHIELDING. To deactivate:

≥ EMF : OFF ▼

Note: If EMF is disabled, the energy of electrons/positrons/photons is deposited on the spot.

- Energy range: e<sup>±</sup>: 1 keV 1000 TeV, γ: 100 eV 1000 TeV
- Up-to-date γ cross sections from the EPDL database
- Energy conservation is ensured within computer precision



# Full coupling between EM and hadronic shower

- E.g. 35-MeV photons on W target
- Start with a purely EM shower
- Photons may undergo photonuclear reactions
- E.g. neutrons can be produced (!)

• Let's examine various particle fluences....





#### Particle fluences from 35-MeV photons on W



35-MeV photons

All fluences in 1/cm<sup>2</sup>/primary photon



### Note of caution for photonuclear interactions

- Are discussed in more detail during the Hadronic physics lecture
- Are not on by default (!). You request them via the **PHOTONUC** card

▶ PHOTONUC Type: ▼ All E: On ▼ E>0.7GeV: off ▼ △ resonance: off ▼ Quasi D: off ▼ Giant Dipole: off ▼ Mat: BLCKHOLE ▼ to Mat: @LASTMAT ▼ Step: 1

 Are suppressed compared to other processes. In a next lecture, we will introduce biasing techniques, which allow to effectively sample these rare (but important!) events. For completeness, one can request to shorten the mean free path for this process (e.g. factor 50-100) with the LAM-BIAS card





### **FLUKA card summary**

**EMF** : transport of electrons, positrons, and photons on/off

...and for photonuclear reactions:

**PHOTONUC** : activate photonuclear reactions

**LAM-BIAS** : transport of electrons, positrons, and photons on/off



#### **EM thresholds**



#### The transport threshold

• In a MC simulation, particles are tracked until they either

- Leave the simulation geometry
- Their energy drops below a predefined value, the transport threshold
- Every **DEFAULT** defines values for transport and delta-ray-production thresholds
- One should not blindly rely on the default values. They depend on
  - the dimensions of your geometry
  - the granularity of your scoring grids



## **Setting transport thresholds**

• For electrons, positrons and photons:

EMFCUT Type: transport e-e+ Threshold: Kinetic Reg: TARGET to Reg: Step:

• For charged hadrons, muons, and ions:

PART-THR Type: Energy VE: 1e-05 Part: PROTON V to Part: PROTON VStep:

CAREFUL: if you set from particle to particle, you may inadvertently kill lowenergy neutrons (can be transported down to 10<sup>-14</sup> GeV)

• For heavy ions: scaled from 4-HELIUM with mass ratio



# Example: 10-MeV e<sup>-</sup> in water

Let 10 MeV electrons impinge on water from the left Cartesian USRBIN with bin height=width=depth of 50  $\mu$ m

#### What are meaningful threshold values?

Threshold too high

 $\rightarrow$  premature: electrons could have traveled further

Threshold too low

 $\rightarrow$  waste of time without gaining anything on the results



Put transport threshold at energy such that the range is smaller than the bin length



 $\overrightarrow{w}$  = h = 50 um

# **Quick way to examine particle ranges**

*Electrons.* <u>https://physics.nist.gov/PhysRefData/Star/Text/ESTAR.html</u> *Protons:* <u>https://physics.nist.gov/PhysRefData/Star/Text/PSTAR.html</u>





### **Electron range in water**

Consider our example scoring with dimensions of 50 µm.

What if we kill electrons below 1 MeV?

- Range at 1 MeV is ~5 mm = 5000 um
- The geometry has L = 50 um
- We would end the transport prematurely and get distorted energy deposition maps
- Let's consider a range of 10 µm
- Depositing them on the spot in a 50µm bin is reasonable
- Corresponding energy is ~20 keV



If your geometries/scoring grids are coarser, higher thresholds can be perfectly fine!



# Summary: how to set your thresholds ?

#### <u>e+/e- and $\gamma$ transport thresholds</u>

- Values depend on the geometry granularity
- Refer to range tables

#### e+/e- and γ production thresholds

At least equal to transport threshold

#### <u>δ-ray production thresholds</u>

- At least equal to e- transport threshold, otherwise wasting cpu-time producing and dumping electrons on the spot
- If transport threshold is lower than δ-ray production threshold, it is increased automatically

#### WARNING



- Photons travel farther than electrons: their thresholds should be lower than for electrons
- Low thresholds for e-/e+/γ are ruthless CPU-time consumers

### **Check e<sup>-+</sup>/photon transport thresholds in \*.out**

Correspond Regio	lence of reg n	ions and E EMF	EMF-FLUK	A mater	ial numbers FLUKA	and names:			
1	0	VACUUM		1	BLCKHOLE				
Ecut =	0.0000E+00	MeV, F	Pcut =	9.0000E	+00 MeV,	BIAS = F,	Ray. = F,	S(q,Z) = F,	Pz(q,Z) = F
2	Θ	VACUUM		2	VACUUM				
Ecut =	0.0000E+00	MeV, F	Pcut =	0.0000E	+00 MeV,	BIAS = F,	Ray. = F,	S(q,Z) = F,	Pz(q,Z) = F
3	1	WATER		26	WATER				
Ecut =	6.1100E-01	MeV, F	Pcut =	5.0000E	-03 MeV,	BIAS = F,	Ray. = T,	S(q,Z) = T,	Pz(q,Z) = T
4	2	LEAD		17	LEAD				
Ecut =	6.1100E-01	MeV, F	Pcut =	5.0000E	-03 MeV,	BIAS = F,	Ray. = T,	S(q,Z) = T,	Pz(q,Z) = T
5	3	ALUMINUM		10	ALUMINUM		<b>,</b>		
Ecut =	6.1100E-01	MeV, F	Pcut =	5.0000E	-03 MeV,	BIAS = F,	Ray. = T,	S(q,Z) = T,	Pz(q,Z) = T
-	Correspond Regio Ecut = 2 Ecut = 3 Ecut = 4 Ecut = 5 Ecut =	Correspondence of reg Region 1 0 Ecut = 0.0000E+00 2 0 Ecut = 0.0000E+00 3 1 Ecut = 6.1100E-01 4 2 Ecut = 6.1100E-01 5 3 Ecut = 6.1100E-01	Correspondence of regions and H Region EMF 1 0 VACUUM Ecut = 0.0000E+00 MeV, H 2 0 VACUUM Ecut = 0.0000E+00 MeV, H 3 1 WATER Ecut = 6.1100E-01 MeV, H 5 3 ALUMINUM Ecut = 6.1100E-01 MeV, H	Correspondence of regions and EMF-FLUKA Region EMF $ \begin{array}{ccccccccccccccccccccccccccccccccccc$	Correspondence of regions and EMF-FLUKA mater         Region       EMF         1       0       VACUUM       1         Ecut =       0.0000E+00       MeV,       Pcut =       0.0000E         2       0       VACUUM       2         Ecut =       0.0000E+00       MeV,       Pcut =       0.0000E         3       1       WATER       26         Ecut =       6.1100E-01       MeV,       Pcut =       5.0000E         4       2       LEAD       17         Ecut =       6.1100E-01       MeV,       Pcut =       5.0000E         5       3       ALUMINUM       10         Ecut =       6.1100E-01       MeV,       Pcut =       5.0000E	$\begin{array}{cccc} \mbox{Correspondence of regions and EMF-FLUKA material numbers} \\ \mbox{Region} & \mbox{EMF} & \mbox{FLUKA} \end{array} \\ \label{eq:correspondence} \begin{tabular}{lllllllllllllllllllllllllllllllllll$	Correspondence of regions and EMF-FLUKA material numbers and names: RegionRegionEMFFLUKA10VACUUMEcut =0.0000E+00MeV, V,Pcut =0VACUUM220VACUUMEcut =0.0000E+00MeV, V, VACUUMPcut =00.0000E+00MeV, V, Pcut =Pcut =00.0000E+00MeV, V, VCUUMPcut =00.0000E+00MeV, V, Pcut =BIAS = F, S31WATER VATER26Ecut =6.1100E-01MeV, MeV, Pcut =Pcut =53ALUMINUM NUM10Ecut =6.1100E-01MeV, MeV, Pcut =Pcut =53ALUMINUM NUM10Ecut =6.1100E-01MeV, MeV,Pcut =53ALUMINUM NUM10Ecut =6.1100E-01MeV, MeV,Pcut =50000E-03MeV, MeV,BIAS = F,	Correspondence of regions and EMF-FLUKA material numbers and names: Region $Region$ $EMF$ $FLUKA$ $I$ $0$ $VACUUM$ $I$ $Ecut =$ $0.0000E+00$ $MeV$ , $2$ $Pcut =$ $0.0000E+00$ $MeV$ , $2$ $BIAS = F$ , $2$ $Ray. = F$ , $2$ $Ray. =$ $0.0000E+00$ $MeV$ , $2$ $Pcut =$ $0.0000E+00$ $MeV$ , $2$ $BIAS = F$ , $2$ $Ray. = F$ , $2$ $Ray. =$ $0.0000E+00$ $MeV$ , $2$ $Pcut =$ $0.0000E+00$ $MeV$ , $2$ $BIAS = F$ , $2$ $Ray. = F$ , $2$ $Ray. =$ $1$ $WATER$ $26$ $WATER$ $BIAS = F$ , $26$ $Ray. = T$ , $26$ $ALUMINUM$ $Ray. =$ $1.00E-01$ $MeV$ , $2$ $Pcut =$ $5.0000E-03$ $MeV$ , $10$ $BIAS = F$ , $Ray. = T$ , $ALUMINUM$ $Ray. = T$ , $Ray. = T$ , $Ray. =$ $6.1100E-01$ $MeV$ , $Nev$ , $Nev =$ $Pcut =$ $5.0000E-03$ $MeV$ , $Nev$ , $Nev =$ $BIAS = F$ , $Ray. = T$ , $Ray. =$ $6.1100E-01$ $MeV$ , $Nev =$ $Nev$ , $Nev =$ $Nev$ , $Nev =$ $BIAS = F$ , $Ray. = T$ ,	Correspondence of regions and EMF-FLUKA material numbers and names: Region EMF FLUKA $I$ BLCKHOLE Ecut = 0.0000E+00 MeV, Pcut = 0.0000E+00 MeV, BIAS = F, Ray. = F, $S(q,Z) = F$ , 2 0 VACUUM 2 VACUUM Ecut = 0.0000E+00 MeV, Pcut = 0.0000E+00 MeV, BIAS = F, Ray. = F, $S(q,Z) = F$ , 3 1 WATER 26 WATER Ecut = 6.1100E-01 MeV, Pcut = 5.0000E-03 MeV, BIAS = F, Ray. = T, $S(q,Z) = T$ , 4 2 LEAD 17 LEAD Ecut = 6.1100E-01 MeV, Pcut = 5.0000E-03 MeV, BIAS = F, Ray. = T, $S(q,Z) = T$ , 5 3 ALUMINUM 10 ALUMINUM Ecut = 6.1100E-01 MeV, Pcut = 5.0000E-03 MeV, BIAS = F, Ray. = T, $S(q,Z) = T$ ,

- Ecut: electron transport threshold given as total energy (!) in MeV
- Pcut: photon transport threshold in MeV



#### **Other particle transport thresholds in \*.out**

=== Particle transport thresholds:

Global cut-off kinetic energy for particle transport: 1.000E-04 GeV The cut-off kinetic energy is superseded by individual particle thresholds if set

Cut-off kinetic energy for 4-HELIUM transport: 1.000E-04 GeV Cut-off kinetic energy for 3-HELIUM transport: 1.000E-04 GeV Cut-off kinetic energy for TRITON transport: 1.000E-04 GeV Cut-off kinetic energy for DEUTERON transport: 1.000E-04 GeV Cut-off kinetic energy for PROTON transport: 1.000E-04 GeV Cut-off kinetic energy for APROTON transport: 1.000E-04 GeV Cut-off kinetic energy for ELECTRON transport defined in the Emfcut card Cut-off kinetic energy for POSITRON transport defined in the Emfcut card Cut-off kinetic energy for NEUTRIE transport: 0.000E+00 GeV Cut-off kinetic energy for ANEUTRIE transport: 0.000E+00 GeV Cut-off kinetic energy for PHOTON transport defined in the Emfcut card Cut-off kinetic energy for NEUTRON transport: 1.000E-14 GeV



#### Electron and photon production thresholds in the .out file

1 Quantities/Biasing associated with each media:

```
WATER
                      g/cm**3
     Rho =
             1.00000
                                     Rlc=
                                             36.0830
                                                        cm
     Ae =
         0.610999
                              Ue =
                                      11521.6
                        MeV
                                                   MeV
           5.000000E-03 MeV
                               Up =
                                       11521.1
    Ap =
                                                   MeV
    dE/dx fluctuations activated for this medium, level 1
    below the threshold for explicit secondary electron production
    (up to 2I discrete levels, up to 2 K-edges)
LEAD
     Rho =
             11.3500
                        q/cm**3
                                     Rlc= 0.561207
                                                        CM
          0.610999
     Ae =
                              Ue =
                                      11521.6
                        MeV
                                                   MeV
           5.000000E-03 MeV
                               Up =
                                      11521.1
     Ap =
                                                   MeV
    dE/dx fluctuations activated for this medium, level 1
    below the threshold for explicit secondary electron production
    (up to 2I discrete levels, up to 2 K-edges)
ALUMINUM
     Rho =
             2.69900
                         g/cm**3
                                     Rlc=
                                            8.89633
                                                        cm
     Ae =
           0.610999
                        MeV
                              Ue =
                                       11521.6
                                                   MeV
           5.000000E-03 MeV
                              Up =
                                      11521.1
    = qA
                                                   MeV
    dE/dx fluctuations activated for this medium, level 1
     below the threshold for explicit secondary electron production
    (up to 2I discrete levels, up to 2 K-edges)
```

- Ae: delta-ray production threshold, given as total energy (!) in MeV
- Ap: photon production threshold in MeV



## **FLUKA card summary**

**EMFCUT** : transport thresholds for electrons, positrons, and photons **PART-THR** : transport thresholds for hadrons, muons, and ions



### The FUDGEM parameter (avoid a FLUKA stop!)

When setting the delta-ray-production threshold,

EMFCUT Type: PROD-CUT 
 e-e+ Threshold: Kinetic 
 e-e+ Ekin: 1e-05 γ: 1e-6
 Fudgem: Mat: ALUMINUM 
 to Mat: ALUMINUM

If you forget to set the Fudgem field the code will stop with:

\*\*\* Atomic electron contribution to mcs for material XXXXX set to 0, are you sure? \*\*\* \*\*\* if so, re-enter it as 1.0e-05 and run again, if not check the manual for the \*\*\* \*\*\* EMFCUT card, PROD-CUT, WHAT(3), execution stopped meanwhile \*\*\*



# The FUDGEM parameter (avoid a FLUKA stop!)

• Setting delta-ray production threshold there's a mysterious parameter called FUDGEM:

**EMFCUT** Type: PROD-CUT ▼ e-e+ Threshold: Kinetic ▼ e-e+ Ekin: 1e-05 γ: 1e-6 Fudgem: 1e-5 Mat: ALUMINUM ▼ to Mat: ALUMINUM ▼ Step:

- Collisions with atomic electrons also contribute to angular deflection
- (Simplified) way to account for them: enhance Z<sup>2</sup> in Rutherford cross-section as Z<sup>2</sup>+Z=Z(Z+1)
- For low delta-ray production threshold  $T_{\delta}$  we could inadvertently incur a double counting in the average projectile deflection due to collisions with atomic electrons:
  - Once when explicitly generating delta-rays
  - Again in Coulomb scattering (via the +Z above)
- For high  $T_{\delta}$  no problem: effect accounted via multiple Coulomb scattering
- The main idea: Z(Z+FUDGEM):
  - For  $T_{\delta}$  much larger than ~30 keV, FUDGEM=1
  - For smaller  $T_{\delta}$  linearly interpolate such that for  $T_{\delta} \sim 1$  keV, FUDGEM=1e-5 (zero)



### **FLUKA card summary**

**EMFCUT** : careful with FUDGEM

**MULSOPT** : request single scattering, fine-tune MCS parameters



### Summary

#### General overview of EM interactions

- Charged particles
  - Coulomb scattering  $\rightarrow$  deflection
  - Ionization  $\rightarrow$  energy loss
  - Radiative effects
- Photons
  - Photo-electric
  - Compton
  - Pair production
- Interdependence of e+/e- and photon cascades (and hadronic)
- Importance of the thresholds !

#### And now

Practical application of thresholds and their effect on your simulation

- Accuracy
- CPU time





### **Beyond the "simple" picture of energy loss**

#### Electrons



**Figure 3.15**: Radiative and collision stopping powers for electrons in aluminium, silver (×10) and gold (×100) as functions of the kinetic energy (solid and dashed curves, respectively). Dot-dashed lines represent the high-energy approximation given by Eq. (3.160). Diamonds indicate the critical energy  $E_{\rm crit}$  at which the radiative stopping power starts dominating for each material.



#### **FLUKA**

# **Dosimetry in micrometric volumes**

- Energy deposition by a 100-MeV p beam in a 1 um<sup>3</sup> Si detector volume immersed in a 10 um<sup>3</sup> Si volume
- Spikes due to non-applicability of Moliere theory. Mitigated switching to singlescattering (MULSOPT) and restricting maximum step size
- Steps in scored quantities can be further mitigated by shortening step sizes (FLUKAFIX, EMFFIX, STEPSIZE)





# **Stopping power of charged particles**

Spin-0 particles:  

$$\begin{array}{l} \sim \ln \beta^{4} \gamma^{4} \\ \text{relativistic rise} \\ \left(\frac{dE}{dx}\right)_{0} = \frac{2\pi n_{e}r_{e}^{2}m_{e}c^{2}z^{2}}{\beta^{2}} \left[ \ln \left(\frac{2m_{e}c^{2}\beta^{2}T_{\max}}{I^{2}(1-\beta^{2})}\right) - 2\beta^{2} + 2zL_{1}(\beta) + 2z^{2}L_{2}(\beta) - 2\frac{C}{Z} - \delta + G \right], \quad T_{t,max} = \frac{2m_{t}\beta_{p}^{2}\gamma_{p}^{2}}{1 + 2\left(\frac{m_{t}}{m_{p}}\right)\gamma_{p} + \left(\frac{m_{t}}{m_{p}}\right)^{2}} \end{array}$$

- z : projectile charge
  - $n_e$ : material electron density (~Z/A)
  - *I*<sup>°</sup>: mean excitation energy
- Bethe formula: 1<sup>st</sup>-order perturbation theory with plane waves, assuming  $v_p >> v_t$ :
  - $\delta$ : density correction, important at high energies
  - C: is the shell correction, important at low energies
  - $L_1$ : Barkas correction ( $z^3$ )
  - $L_2$ : Bloch ( $z^4$ ) correction
  - G: Mott corrections

